

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination OHMI ET AL.	
		Examiner KEATH T. CHEN	Art Unit 1792	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0132047	09-2002	Yamazaki et al.	427/255.6
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	J	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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